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				Application Number	10/689,024	
				Confirmation Number	4493	
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				First Named Inventor	Takashi UDAGAWA	
				Art Unit	2826	
Examiner Name	Minh Loan Tran	Attorney Docket Number	Q72568			
Sheet	1	of	1			

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
		Number	Kind Code ³ (if known)		
MLT		US 6,069,021		05-30-2000	TERASHIMA et al.
		US			
		US			
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		US			

FOREIGN PATENT DOCUMENTS							
Examiner Initials*	Cite No. ¹	Foreign Patent Document			Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Translation ⁶
		Country Code ³	Number ⁴	Kind Code ⁵ (if known)			
MLT		JP	10-56202		02-24-1998	SHOWA DENKO KK	Abstract
MLT		JP	55-3834		01-26-1980		Abstract
MLT		JP	10-107315		04-24-1998	SHOWA DENKO KK	Abstract

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.	Translation ⁶
MLT		Isamu AKASAKI (compiler), "Advanced Electronics Series, I-21, Group-III Nitride Semiconductor", 1 st edition, pp. 288-289, Baifukan (December 8, 1999)	Abstract
MLT		Isamu AKASAKI et al.; "Effects of AlN Buffer Layer on Crystallographic Structure and on Electrical and Optical Properties of GaN and Ga _{1-x} Al _x N (0 < x ≤ 0.4) Films Grown on Sapphire Substrate by MOVPE"; Journal of Crystal Growth (the Netherlands); Vol. 98, pp. 209-219 (1989)	
MLT		Isamu AKASAKI (compiler); "Advanced Electronics Series, I-21, Group-III Nitride Semiconductor"; 1 st edition, pp. 211-213, Baifukan (December 8, 1999)	Abstract

Examiner Signature	Minh Loan Tran	Date Considered	8/05
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